


<b>Search Notes</b>  	<b>Application/Control No.</b>  10790168	<b>Applicant(s)/Patent Under Reexamination</b>  SOBCHAK ET AL.
	<b>Examiner</b>  Lee, Siu M	<b>Art Unit</b>  2611

SEARCHED			
Class	Subclass	Date	Examiner
375	346, 347, 348, 350, 316, 143, 152, 234, 229	4/12/2007	Siu M. Lee
455	67.11, 63.1, 522	4/12/2007	Siu M. Lee

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	4/12/2007	Siu M. Lee
IEEE	4/12/2007	Siu M. Lee
Discuss application with Chieh Fan	4/12/2007	Siu M. Lee

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner